8th European HICUM Workshop

May 20/21, 2008

Agilent Technologies, Böblingen, Germany

Workshop location: Munich Hall, Agilent Technologies

Herrenberger Straße 130, 71034 Böblingen, Germany

Workshop Organisation: Anindya Mukherjee, Michael Schröter

Local arrangements: Franz Sischka

Agenda

Day 1 (May 20)

10:00 F. Sischka (Agilent), M.Schroter (CEDIC): Welcome and Opening

Session I – Model implementation

10:20 M.Schroter, A.Mukherjee (CEDIC): HICUM – Productization and Support Update
11:00 Z.Huszka (AMS), C. McAndrew (Freescale), G. Coram (Analog Devices): Implementing Ib&Ic correlated noise for bipolar models in SPICE and VERILOG-A
11:40 J.C.Perraud (CAEN): NQS Effect into SPICE using new Improved advanced Verilog-A Model Compiler for SPICE3F5
12:10 Lunch

Session II – Parameter Extraction

13:30 D.Celi (ST): Step by Step Extraction of HICUM/L2 High-Current Parameters
14:10 B.Ardouin (XMOD): Update of XMOD activities
14:50 Z.Huszka, E.Seebacher (AMS): Removing Ambiguity from Hicum/L2 by an Improved GICCR
15:30 Break

Session III – Compact Modeling

16:00 S.Lehmann, M.Schroter (CEDIC): Power HBT Modeling overview
16:40 M.Schroter, S. Lehmann, J.Krause (CEDIC): Compact layout and bias dependent base resistance model for advanced SiGe HBTs
17:20 M.Schroter (CEDIC): DOTFIVE overview and future model development
18:10 Day 1 – Wrap up, Discussions, Demos
19:00 Dinner

Day 2 (May 21)

Session IV – Geometry Scaling / Measurement Techniques

09:00 C.Raya, D.Celi (ST), T.Zimmer(IMS): Investigation of De-embedding Methods up to 110GHz
09:40 Juan M. Lopez-Gonzalez (Universitat Politecnica de Catalunya): Study of Emitter Scaling Effects in 200 GHz SiGe-HBT using TCAD Modeling
10:20 Break

Session V – HICUM/Level0

10:50 C.Thiele (Infineon): Further developments of the HICUM/L0 Model
11:30 N.Derrier(ST): From HICUM/L2 to HICUM/L0
12:10 ALL: workshop wrap-up (discussions, conclusions, plans)
13:00 Adjourn

Note: Presentation time slots include 30min talk and 10min discussion